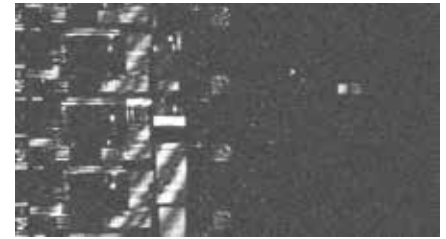
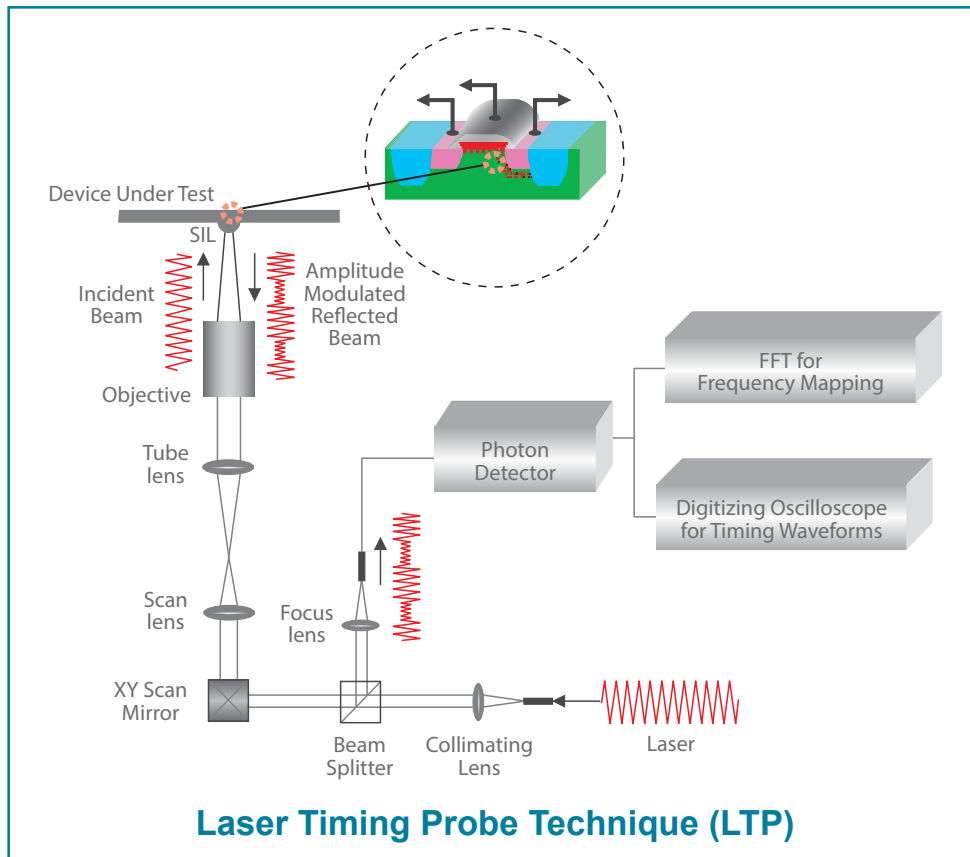
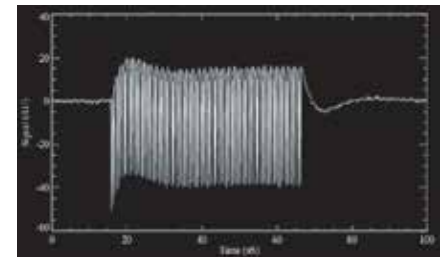


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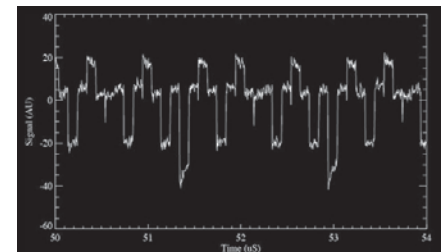
LASER TIMING PROBE TECHNIQUE



Frequency mapping image to locate nodes at specified frequency



Single point waveform measurements to show signal delay of 15 μ s



Timing waveform showing 4 states from a 3-state inverter

Features

- Non-invasive backside detection of waveforms / logic within a die using a CW laser
- FFT Frequency Mapping to quickly trace signal paths inside a die
- Best-in-class:
 - Resolution with Centric and Aplanatic RSILs
 - Bandwidth up to 12 GHz
 - Test loop lengths up to 1000 ms
 - Measure rise times < 40 ps
- Optional:
 - SOM with 1064 nm and 1340 nm lasers
 - PEM with ultra low-noise InGaAs camera (LN₂ or TE cooled)
- Device Thermal Control



SEMICAPS LTP 3000